

<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/748,945	CHEN ET AL.	
				Examiner	Art Unit	
				SHELLEY A. DODSON	1616	

<b>SEARCHED</b>			
Class	Subclass	Date	Examiner
424	65	7/1/2006	SAD
	66		
	68		
	400		
	401		
<i>Search updated SAD 7/2006</i>			

<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
	DATE	EXMR
INVENTOR SEARCH	7/1/2006	SAD <i>SAD</i>
STN SEE ATTACHED	7/1/2206	SAD <i>SAD</i>

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
424	65, 66, 68, 400	7/1/2006	SAD
401			